## Application/Control No. O9/665,715 Notice of References Cited Application/Control No. O9/665,715 Examiner Kim T. Huynh Applicant(s)/Patent Under Reexamination SCHEEL ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,584,539	06-2003	James et al.	710/314
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	D	US-			
	Ε	US-			
	F	US-			
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	к	US-			
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## **NON-PATENT DOCUMENTS**

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